

A 5-DC-parameter MOSFET model for circuit simulation in QucsStudio and SPECTRE

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Outline

- **Introduction**
- **Velocity saturation effects**
- **Parameter extraction**
- **Intrinsic capacitances including velocity saturation and DIBL**
- **Circuit examples**

Introduction: democratizing IC design

Open source PDK



Open source EDA tools



Open source IP & libraries



Available compact MOSFET models

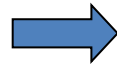


We propose: **simple** 5-DC-parameter
MOSFET model



Velocity saturation effects

Normalized current vs.
normalized charge densities



$$i_D = \frac{(q_S + q_D + 2)}{1 + \zeta|q_S - q_D|} (q_S - q_D)$$

short-channel parameter :

$$\zeta = \frac{(\mu_s \phi_t / L)}{v_{sat}}$$

diffusion-related velocity /saturation velocity

Saturation current due to saturation velocity of the carriers

$$I_{Dsat} = -W Q_{Dsat} v_{sat}$$

Q_{Dsat} is the saturation inversion charge density at the drain end of the channel

or using normalized variables

$$i_{Dsat} = \frac{2}{\zeta} q_{dsat}$$

Physics-based saturation: design model

$$i_{Dsat} = \frac{2}{\zeta} q_{dsat} \qquad i_{Dsat} = \frac{(q_S + q_{Dsat} + 2)}{1 + \zeta(q_S - q_{Dsat})} (q_S - q_{Dsat})$$

$$q_{Dsat} = q_S + 1 + \frac{1}{\zeta} - \sqrt{\left(1 + \frac{1}{\zeta}\right)^2 + \frac{2q_S}{\zeta}}$$

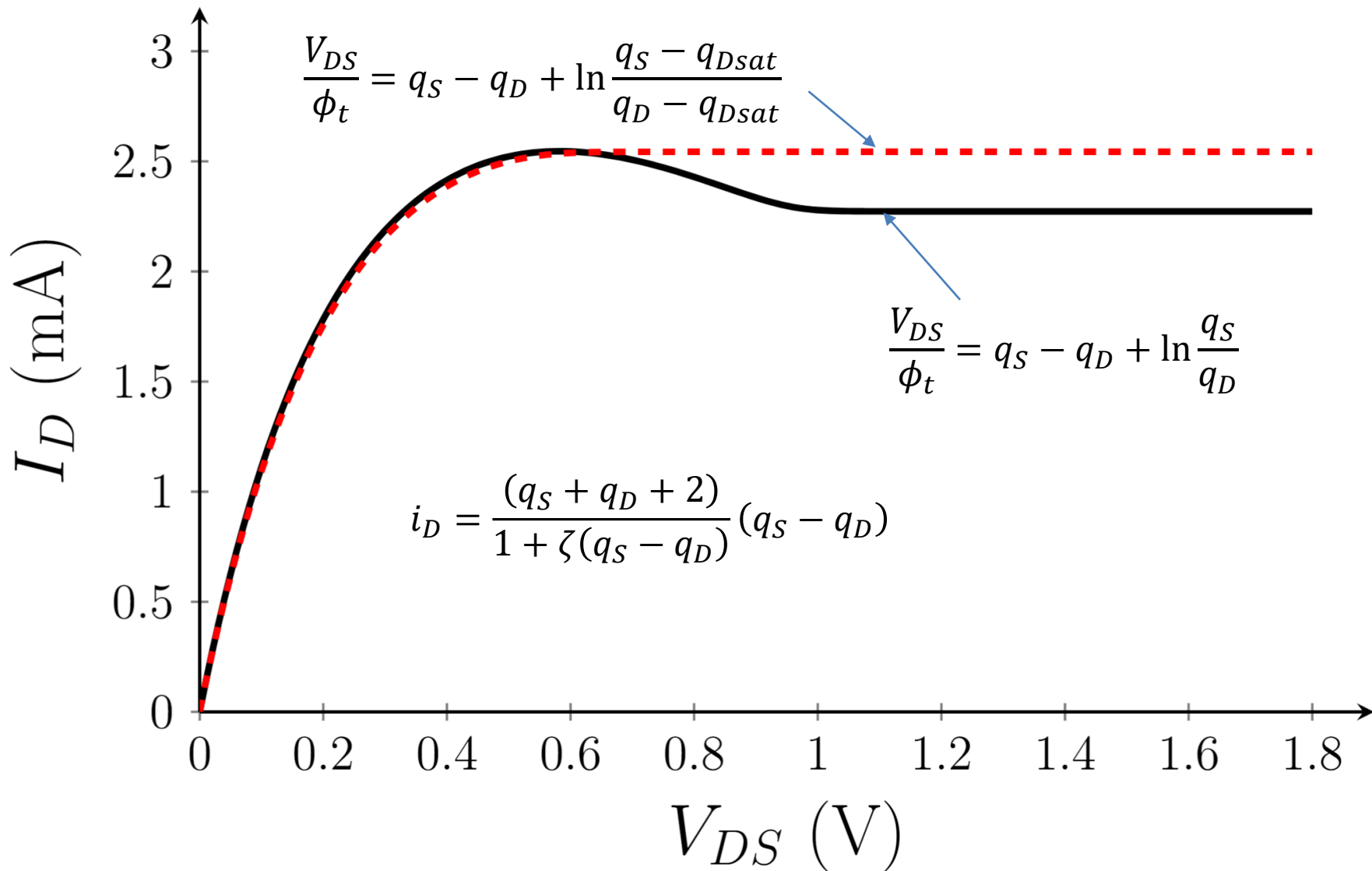
Unified Charge Control Model including the effect of velocity saturation

$$\frac{V_P - V_{SB}}{\phi_t} = q_S - 1 + \ln q_S$$

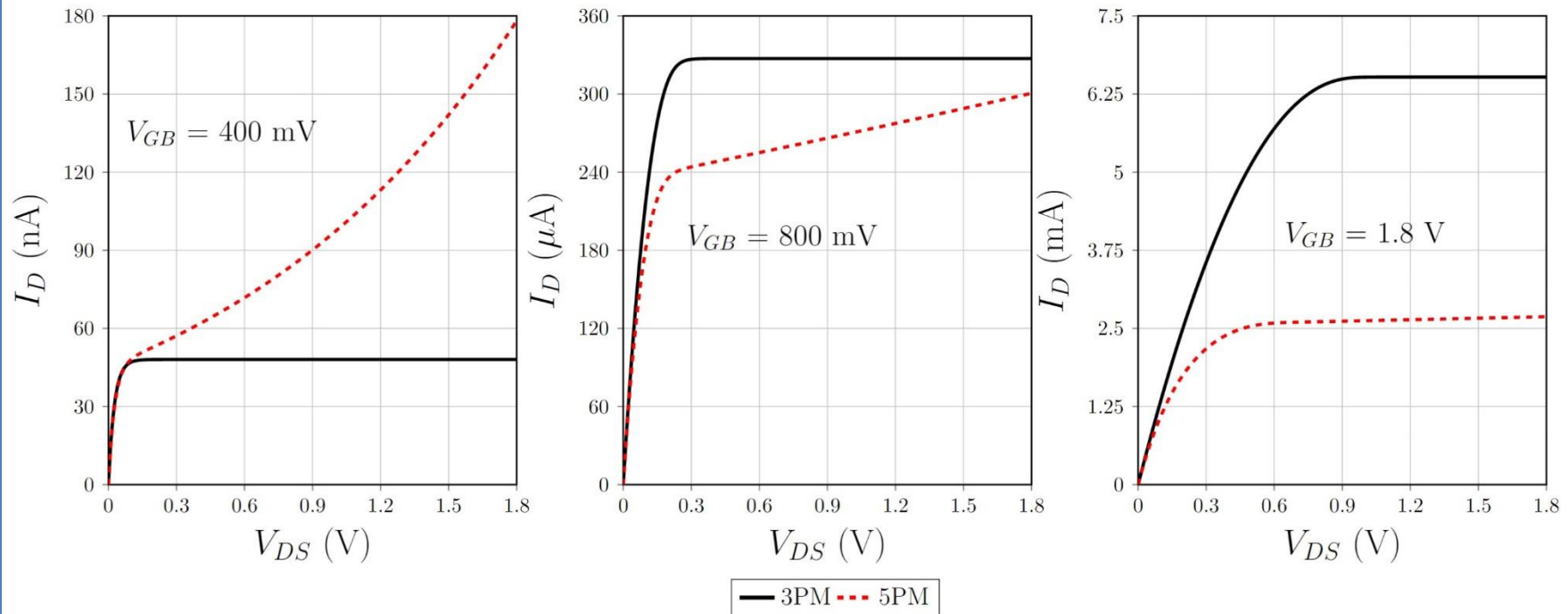
$$\phi_t = 26 \text{ mV@ } 300\text{K}$$

$$\frac{V_{DS}}{\phi_t} = q_S - q_D + \ln \frac{q_S - q_{Dsat}}{q_D - q_{Dsat}}$$

Effect of the maximum of $i_D(q_D)$ on the output characteristic $i_D(v_D)$



Output characteristics including DIBL and v_{sat}



DIBL model: $V_T = V_{T0} - \sigma(V_{SB} + V_{DB})$

Transistor	W/L ($\mu\text{m}/\mu\text{m}$)	V_{T0} (mV)	I_S (μA)	n	σ	ζ
NMOS2V	5/0.18	528	5.52	1.37	0.025	0.056

V_T , I_S and n extraction: The g_m/I_D method

$$g_{ms} = \mu \frac{W}{L} n C_{ox} \phi_t q_S = \frac{2I_S}{\phi_t} q_S$$

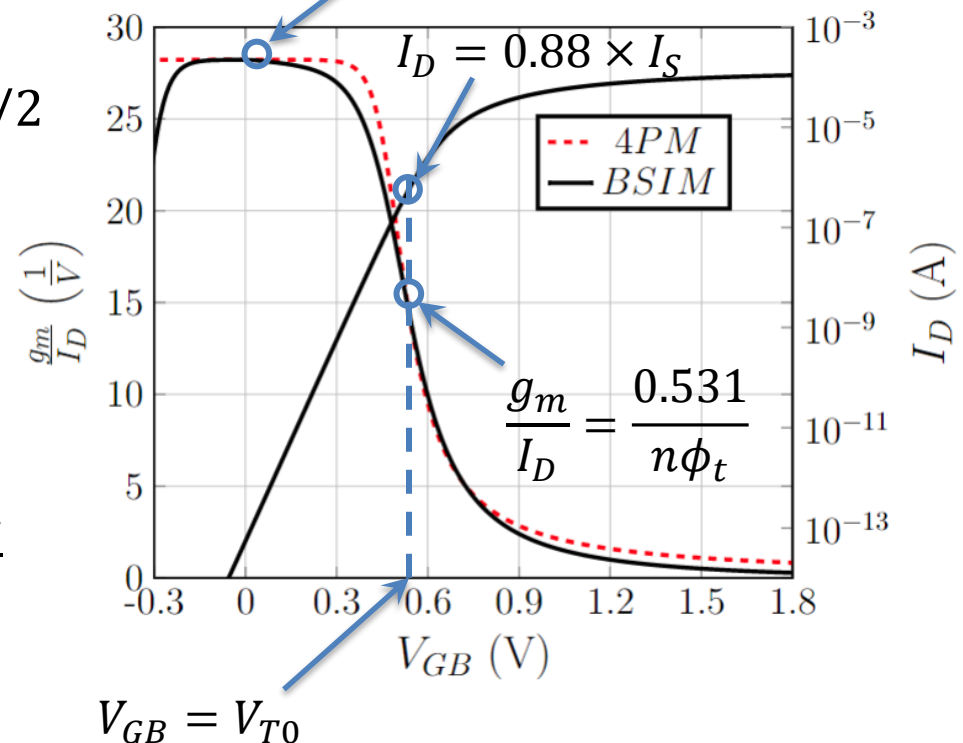
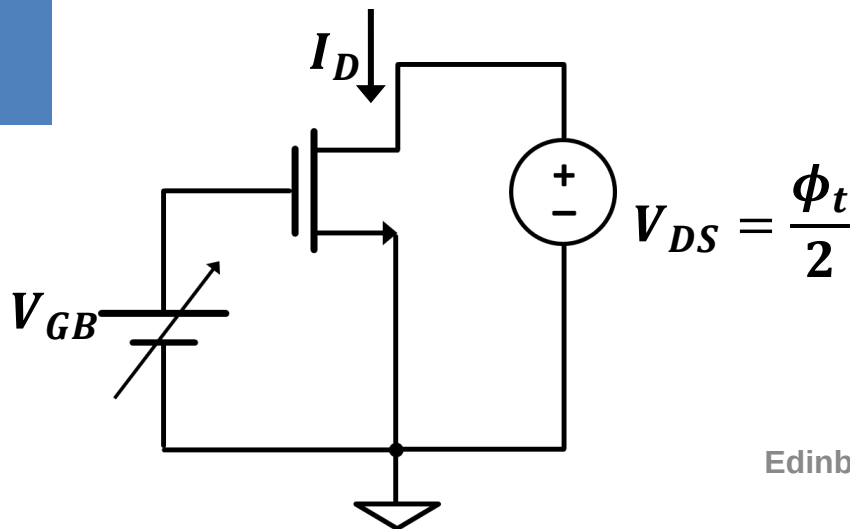
$$\left. \frac{g_m}{I_D} \right|_{V_{DS} \rightarrow 0} = \frac{1}{n\phi_t(1 + q_S)}$$

Thus, at threshold ($q_S = 1$) g_m/I_D is at
 $\frac{1}{2}$ of its maximum value,

$$\left(\frac{g_m}{I_D} \right)_{max} \cong \frac{1}{n\phi_t}$$

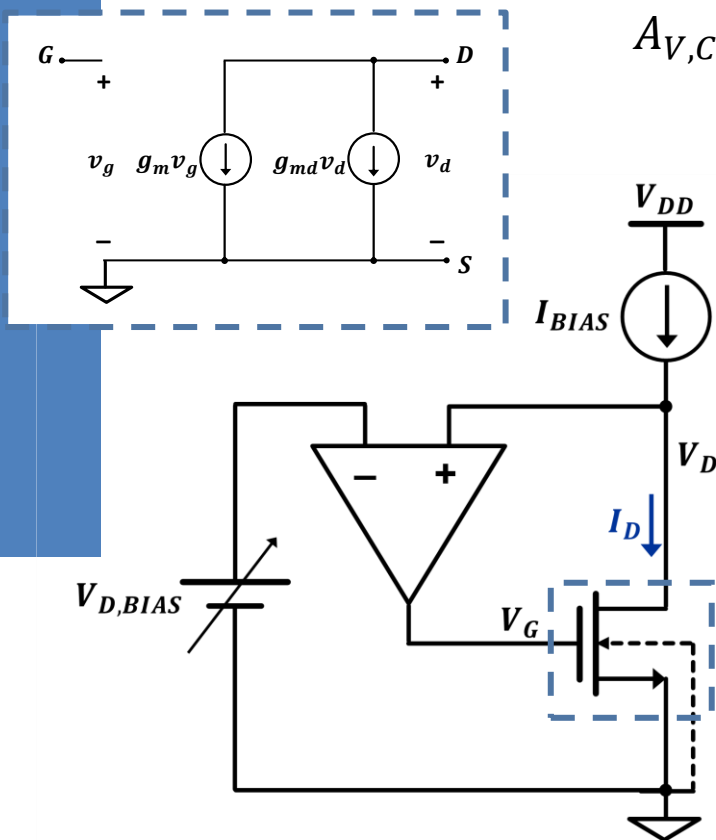
$$I_D(q_S = 1, V_{DS} = \phi_t/2) \cong g_{ms}\phi_t/2$$

$$= \frac{2I_S}{\phi_t} \phi_t/2 = I_S$$

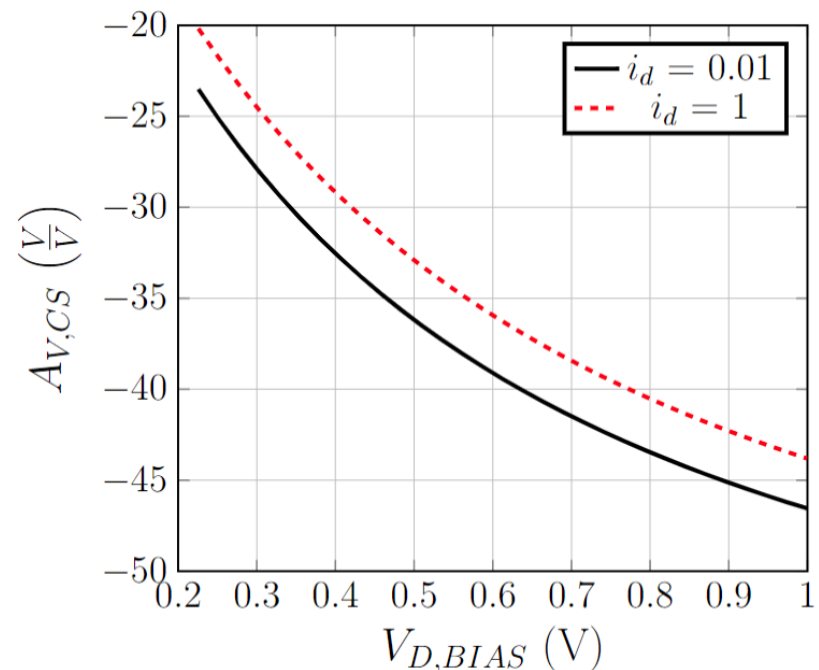


Extraction of σ in WI (MI) in saturation

Common Source Intrinsic Gain method



$$A_{V,CS} = \frac{v_d}{v_g} = -\frac{g_m}{g_{md}} = -\frac{\frac{g_m}{I_{D,sat}}}{\frac{g_{md}}{I_{D,sat}}} = -\frac{\frac{1}{\phi_t} \left(\frac{1}{n}\right) \frac{2}{q_S + 2}}{\frac{1}{\phi_t} \left(\frac{\sigma}{n}\right) \frac{2}{q_S + 2}} = -\frac{1}{\sigma}$$

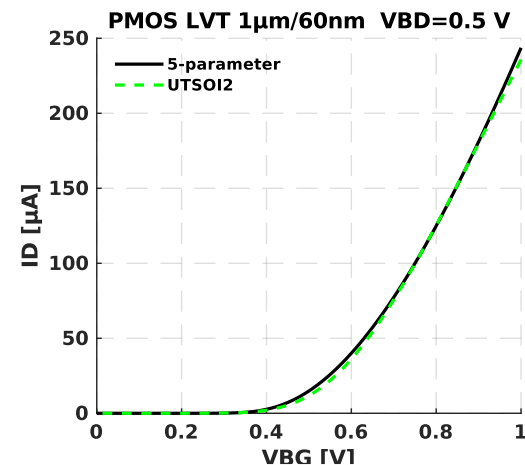
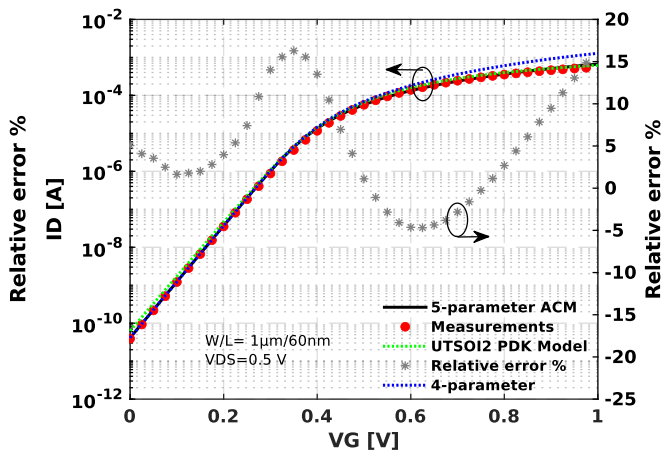
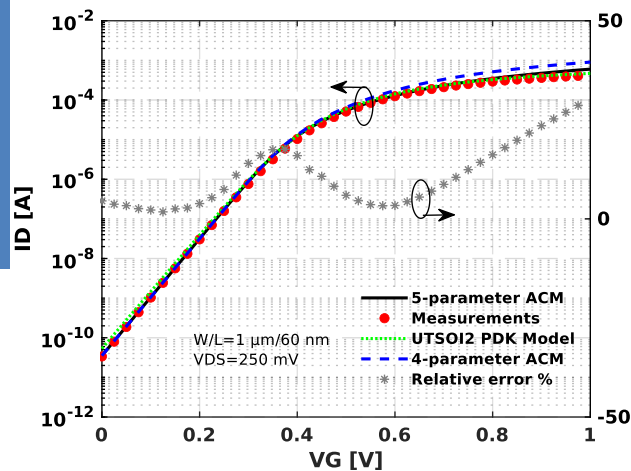


28 nm FD-SOI technology DC characteristics

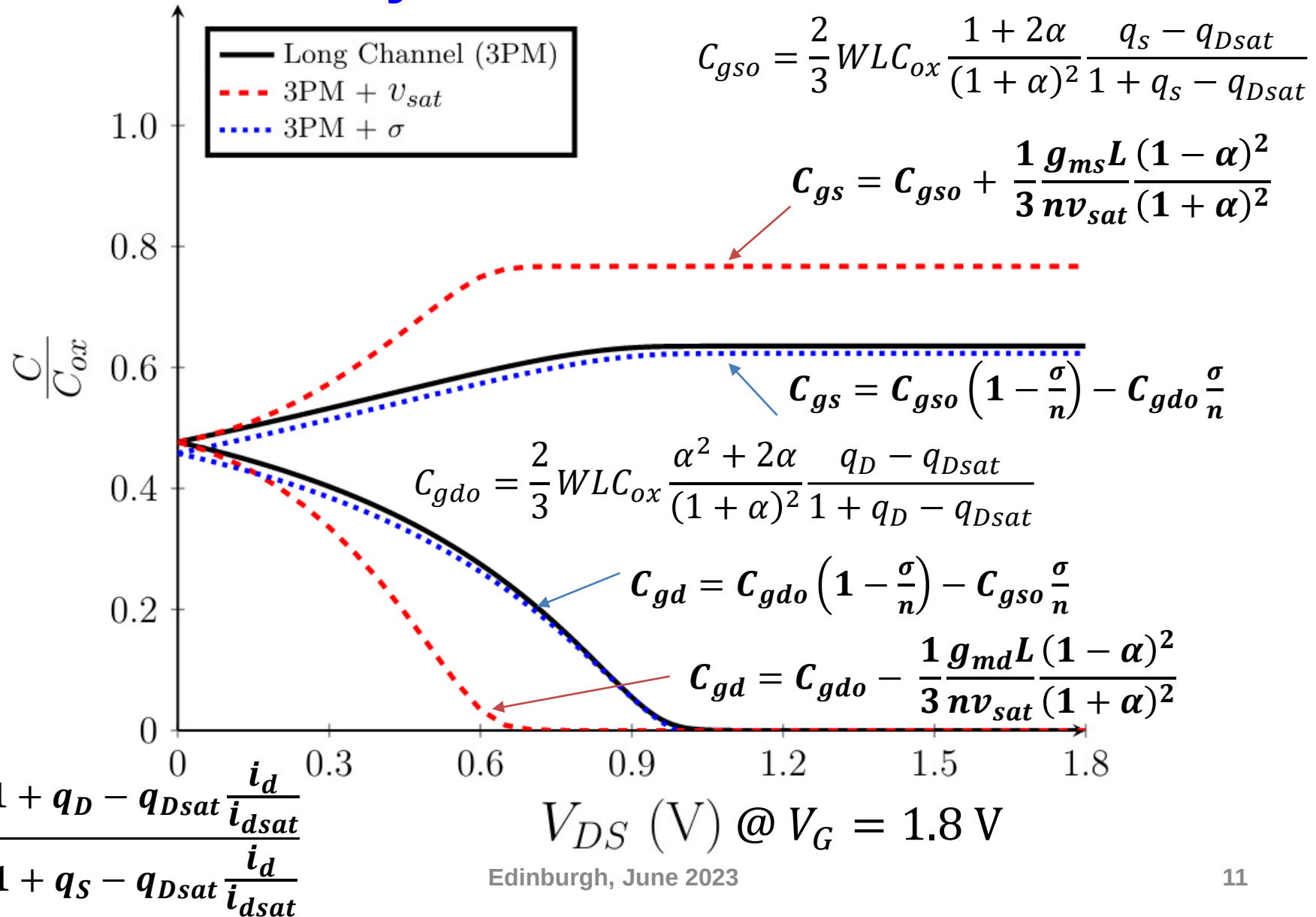
Parameter
extraction
for L=60 nm

Transistor	W/L	V_{T0} (mV)	I_S (μA)	n	σ	ζ
LVTNMOS	1 μm /60 nm	390.5	3.25	1.138	0.018	0.039
LVTNMOS	1 μm /60 nm	390.5	3.25	1.138	0.018	0.039
LVTNPMOS	1 μm /60 nm	403.6	0.755	1.014	0.029	0.024

Model Verification: NMOS & PMOS TRANSISTORS

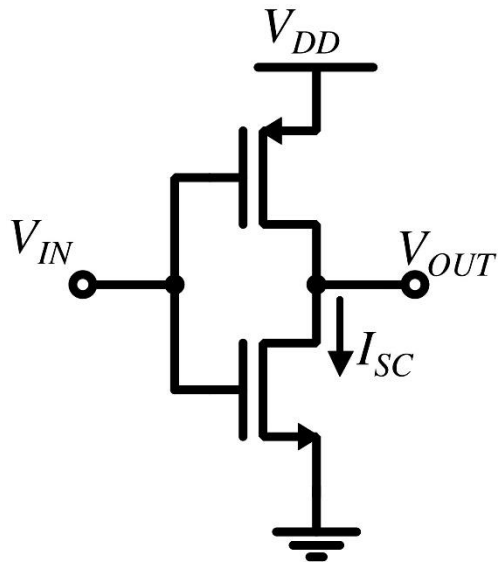


Intrinsic capacitances including velocity saturation and DIBL



CMOS Inverter

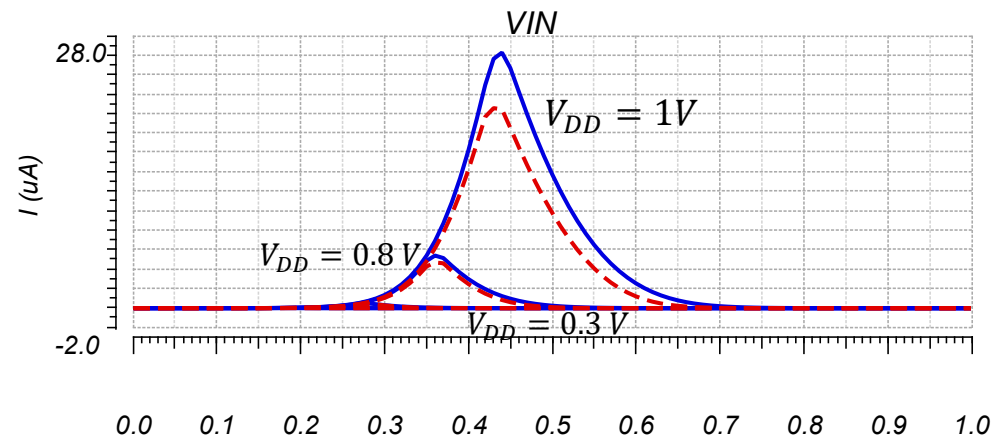
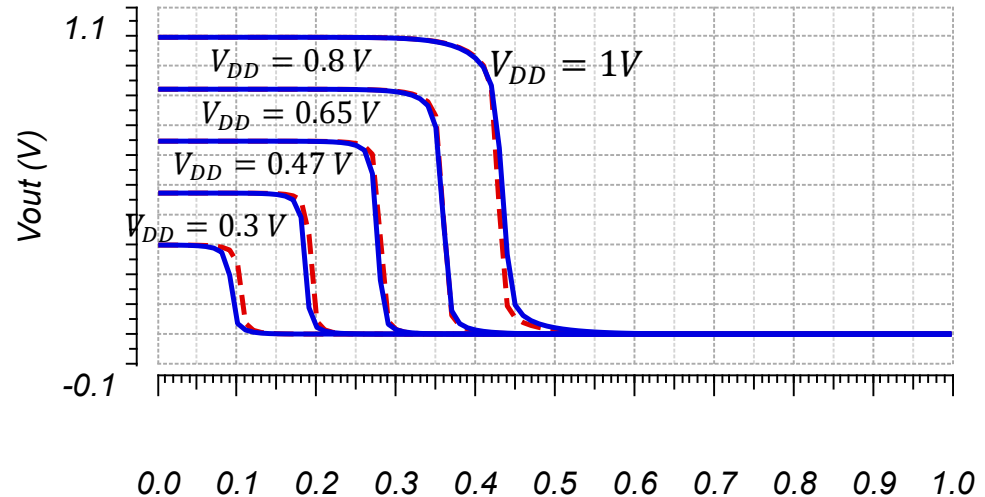
VTC and short-circuit current in 28 nm FD-SOI



$$W_n = W_p = 1 \mu m$$

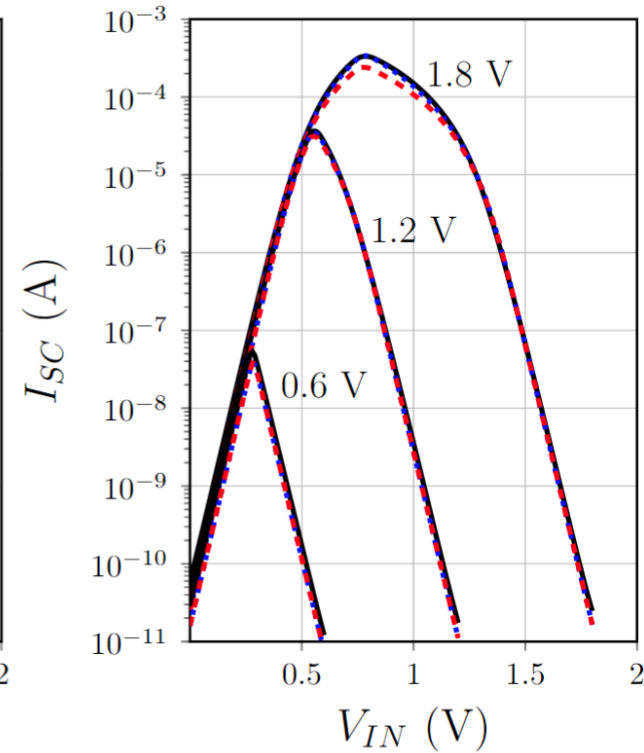
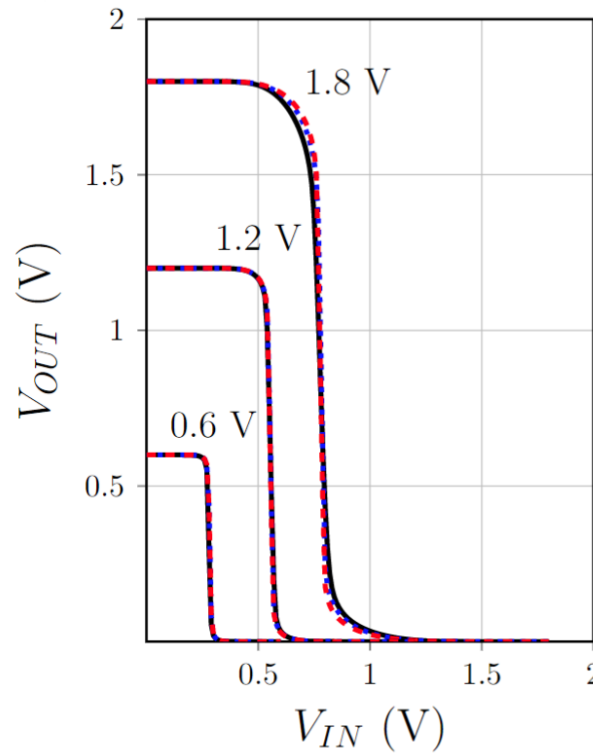
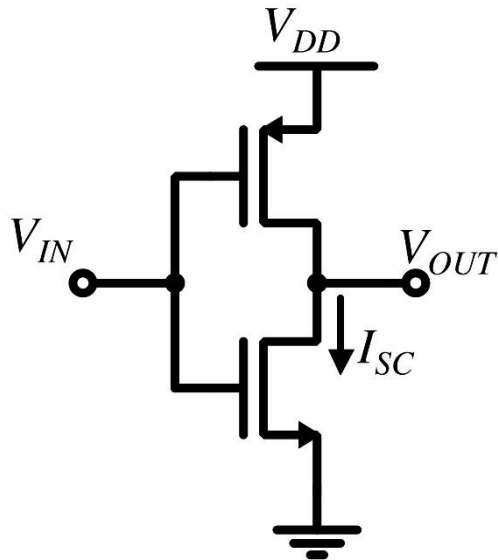
$$L_n = L_p = 60 nm$$

--- 5PM
--- UTSOI2



CMOS Inverter in 180 nm bulk

VTC and short-circuit current

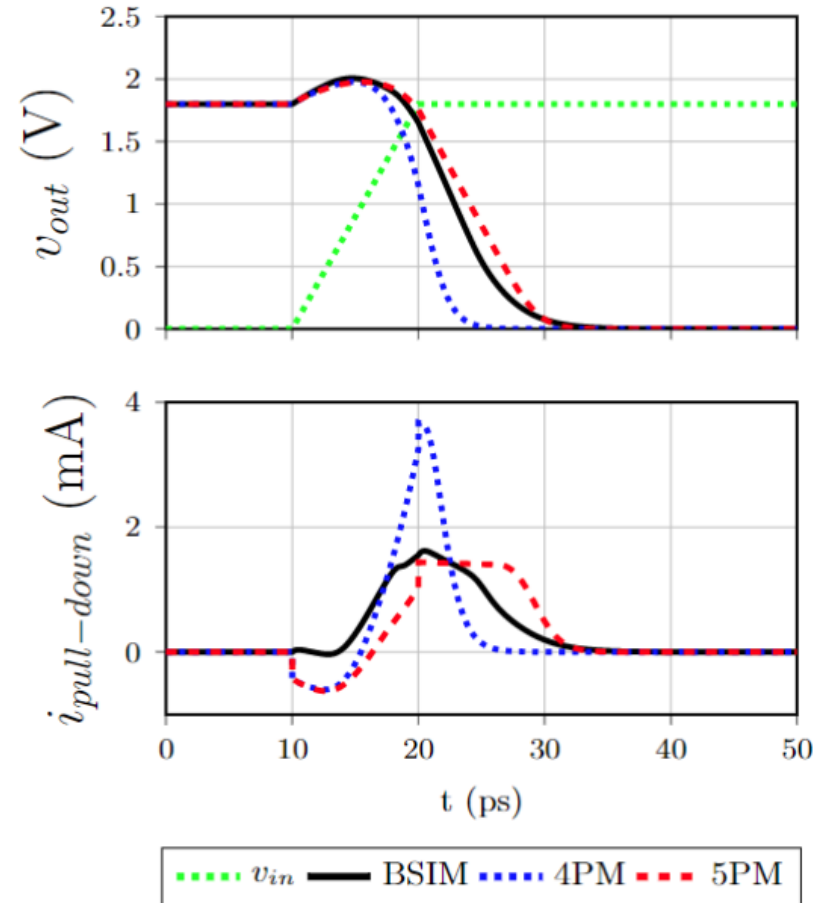
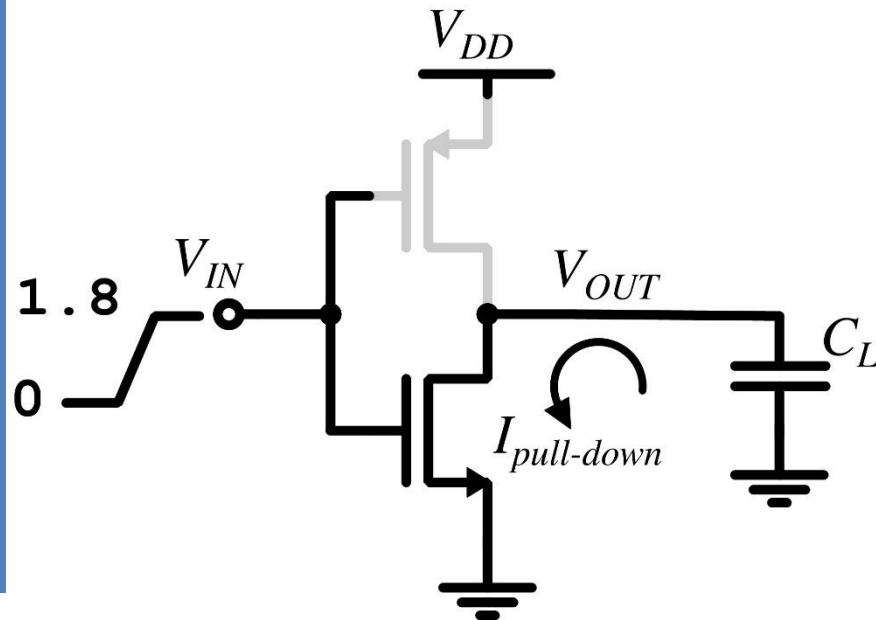


— BSIM ····· 4PM - - - 5PM

Transistor	W/L ($\mu\text{m}/\mu\text{m}$)	V_{T0} (mV)	I_S (μA)	n	σ	ζ
NMOS	5/0.18	528	5.52	1.37	0.027	0.056
PMOS	5/0.18	-525	1.82	1.40	0.024	0.035

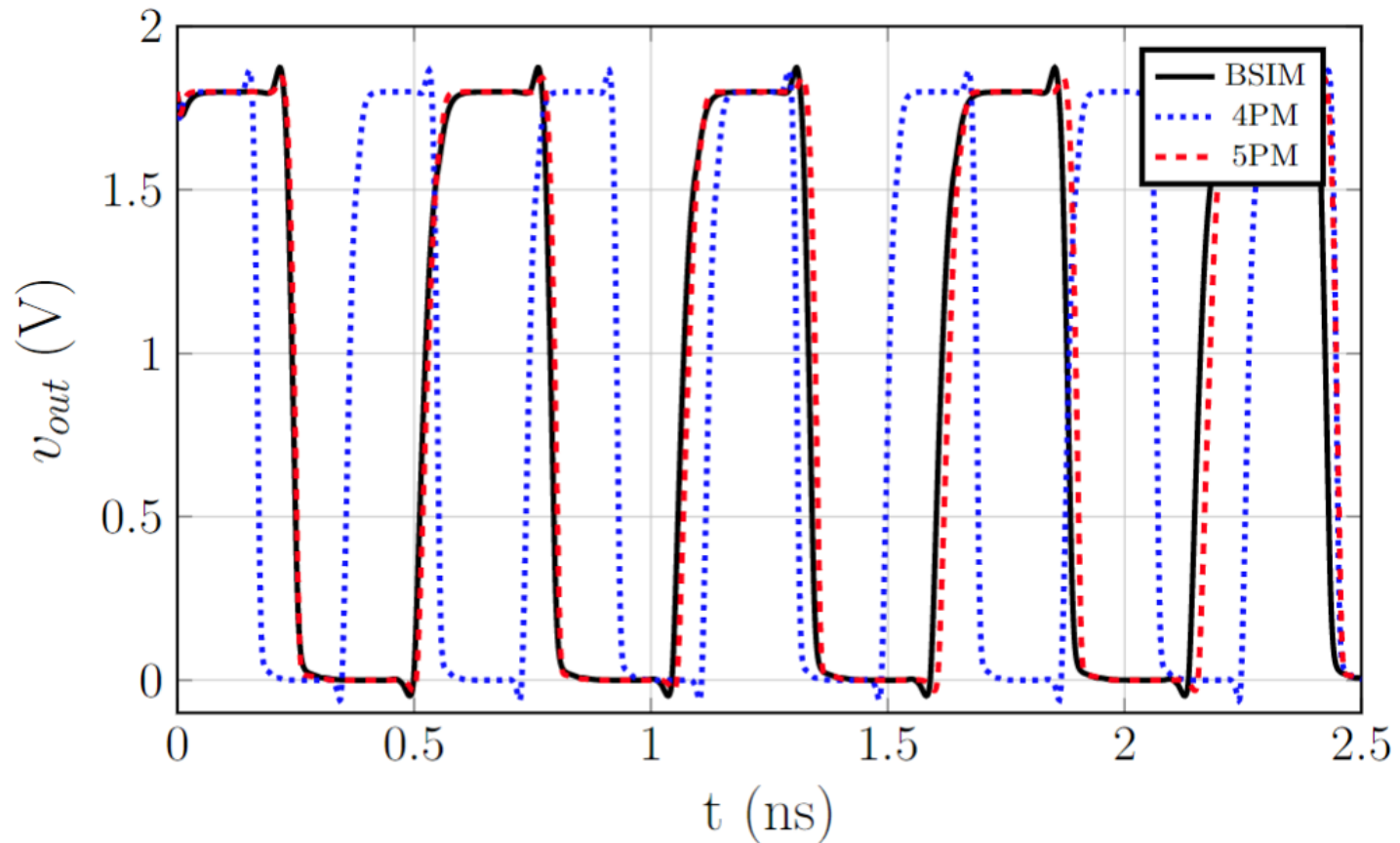
CMOS Inverter in 180 nm bulk

Output Voltage and pull-down current



11- stage Ring Oscillator in 180 nm bulk

Output Voltage



Conclusion

- For the first time, a truly compact MOSFET model for SPICE formulated with single-piece functions
- With only 5 DC parameters that are extracted from simple and direct methods (automatized) using SPICE
- Good matching with circuit simulations with BSIM and UTSOI2 models

Main References

- C. Galup-Montoro and M. C. Schneider, *MOSFET Modeling for circuit analysis and design*, World Scientific, 2007.
- C. M. Adornes, D. G. Alves Neto, M. C. Schneider and C. Galup-Montoro, "Bridging the gap between design and simulation of low-voltage CMOS circuits," *Journal of Low Power Electronics and Applications*, vol. 12, issue 2, June 2022.
- Accellera. Verilog-AMS reference manual. [Online]. Available: <https://www.accellera.org>

